

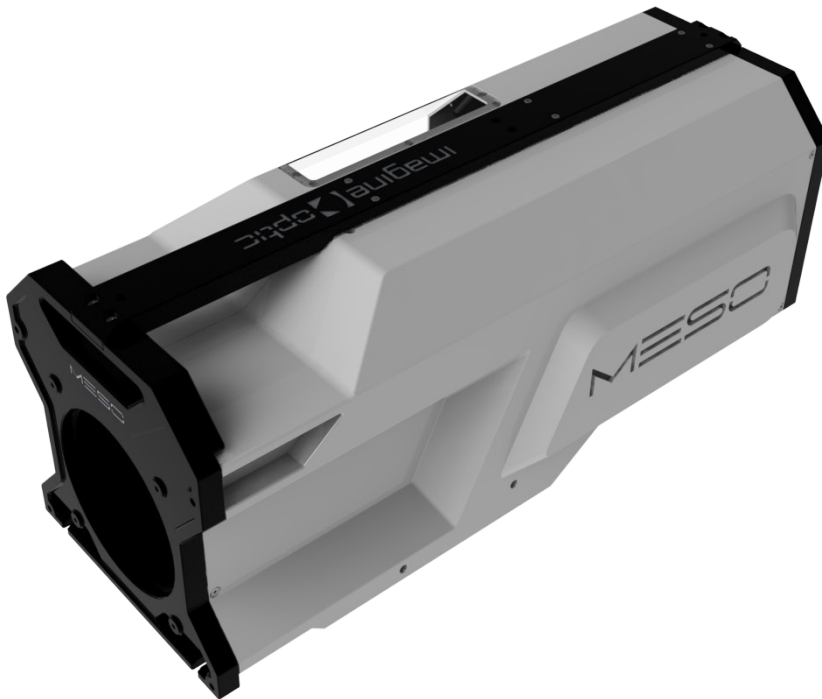


# MESO

Interferometry applications

Simpler, faster, more  
robust

Inensitive to vibrations  
At-wavelength metrology  
Parallel optics testing





## New metrology solution for easy at-wavelength testing of flat surfaces in any environment

MESO is the perfect tool for the characterization of:

- + Parallel Optics
- + Screens
- + Filters, dichroics
- + Mirrors
- + Beamsplitters
- + Windows, substrates
- + Corner cubes
- + Crystals
- + Rods, disks
- + Glass wafers
- + Displays
- + Machined surfaces
- + Windshields
- + Prisms
- + Large lenses
- + Optical systems, beam expanders

## APPLICATIONS

- + In situ process control
- + Thin Parallel Optics characterization
- + Transmitted wavefront quality (TWE)
- + Surface shape & flatness measurement (RWE)
- + Large optics testing
- + Wedge measurement

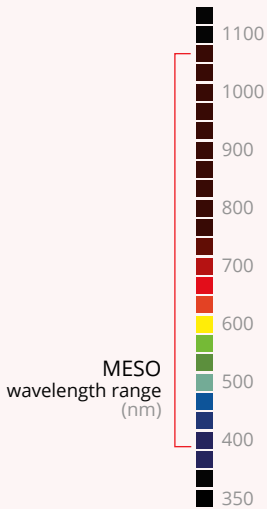
## FEATURES

- + Insensitive to vibrations thanks to fast single shot acquisition and the lack of need for a reference arm for comparison. It allows for a standalone setup compatible with shop floor metrology!
- + At-wavelength sample testing due to its achromatic system embedding up to 4 light sources, automatically controlled by the User Interface.
- + Insensitive to reflections from the back surface of the sample thanks to a unique patent pending method. No surface preparation of the sample is needed, avoiding added steps that could disturb the metrology and put the sample at risk.
- + Smart maintenance: On-site user install or replacement of sources with no opening of optical areas and no realignment needed.



# SPECIFICATIONS

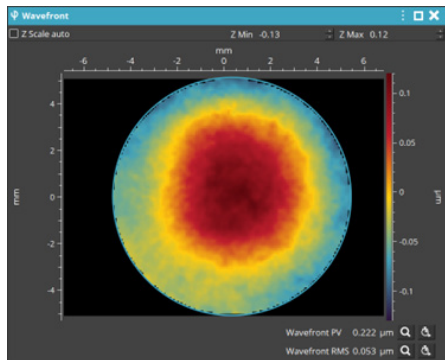
Optical configuration	double-pass
Mounting configuration	horizontal or vertical
Test beam diameters	optical zoom from 1.5" (38.1 mm) up to 6" (152 mm)
Optical axis	4.25" (108 mm)
Calibrated range	405 nm to 1064 nm
Working output wavelengths	custom 405 nm, 488 nm, 520 nm, 635 nm, 785 nm, 830 nm, 1064 nm
Output polarization	optional linear, circular
Phase point resolution	680 x 500
Minimum exposure time	27 $\mu$ s
Camera	4096 x 3000 pixels, 10 bits
Interface	USB 3.0
System software	high performance Dell™ computer & 24" touchscreen, Windows 10, WaveSurf™ acquisition control & analysis software
Warranty	1 year system & laser standard, extendable
Dimension / Weight	63 x 30 x 45 cm / 25 kg
Vibration isolation	not necessary
Compressed air	not necessary
Sample reflectivity	1% - 100%, no attenuation required
Sample min. thickness	100 $\mu$ m
RMS wavefront repeatability*	1 nm



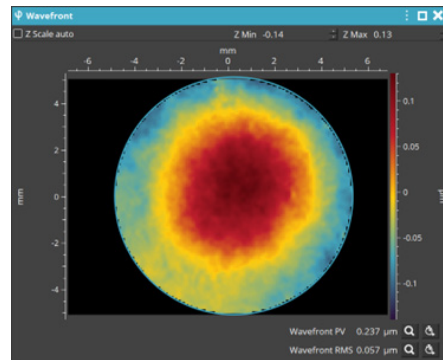
\* From a set of 36 measurements on a Ø4" diameter flat mirror, each of them averaged 16 times, a synthetic reference is defined by the mean of the 18 odd measurements. The RMS wavefront repeatability is then defined by the mean RMS difference plus 2x the standard deviation of the difference between the 18 even measurements and the synthetic reference.

# ACHROMATISM

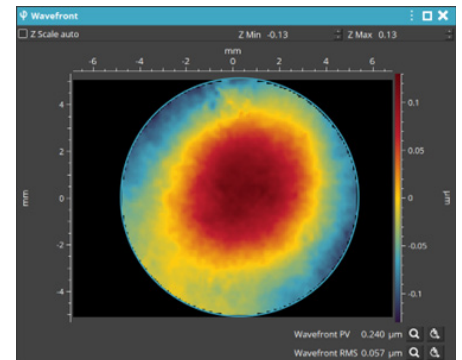
Plane optics measured on Ø4" diameter at 3 wavelengths: wavefront error variation is less than 4 nm RMS ( $< \lambda/150$ )



wavelength: 402 nm  
wfe: 53 nm RMS



wavelength: 635 nm  
wfe: 57 nm RMS



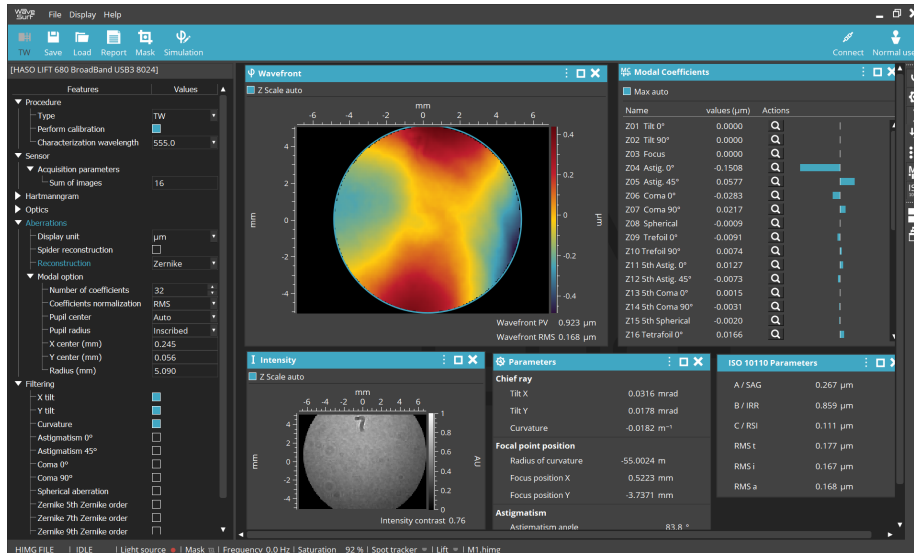
wavelength: 785 nm  
wfe: 57 nm RMS

# SOFTWARE

## WAVESURF™

### Easy-to-use interface

Wavesurf allows operators and engineers in manufacturing environments to perform wavefront and surface characterization of flat optics and large lenses with just a few clicks. Scripted testing procedures guide users through all the steps. It makes control easy, automated and error-proof.



- + Touchscreen interface control
- + Scripted testing procedures guide the user through all the steps
- + Automated control of up to 4 embedded wavelengths
- + Automated control of test diameter (optical zoom)
- + Complete automated test report
- + ISO10110 standard compliance
- + Data format compatible with CODE V® and MetroPro™

## WHITE PAPERS

- + Shop floor measurement: vibration-proofed solutions for optical metrology
- + At-wavelength metrology for optical systems and surfaces
- + Parallel optics testing: simultaneous characterization of both optical faces in laboratory and manufacturing conditions



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